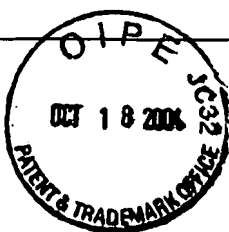


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Page

1

of

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Examiner:

Group Art Unit: 2621

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Examiner /John Lee/

Date Considered: 10/11/2007

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.